

### PCTEST ENGINEERING LABORATORY, INC.

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### **HEARING AID COMPATIBILITY**

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

**Date of Testing:** 12/23/2019 - 12/30/2019 **Test Site/Location:** PCTEST Lab, Columbia, MD, USA **Test Report Serial No.:** 1M1911140188-01.A3L Date of Issue:

FCC ID: A3LSMF700F

APPLICANT: SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: RF Emissions Testing

Application Type: Certification FCC Rule Part(s): CFR §20.19(b) **HAC Standard:** ANSI C63.19-2011

285076 D01 HAC Guidance v05

285076 D02 T-Coil testing for CMRS IP v03

01/07/2020

**DUT Type:** Portable Handset

Model: SM-F700F

Additional Model(s): SM-F700F/DS, SCV47

Test Device Serial No.: Pre-Production Sample [S/N: 4725J]

C63.19-2011 HAC Category: M4 (RF EMISSIONS CATEGORY)

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.







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#### INTRODUCTION 1.

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-86581 to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

### Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

<sup>&</sup>lt;sup>1</sup> FCC Rule & Order, WT Docket 01-309 RM-8658

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#### 2. **DUT DESCRIPTION**



FCC ID: A3LSMF700F

Manufacturer: Samsung Electronics Co., Ltd.

129, Samsung-ro, Maetan dong,

Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Model: SM-F700F

Additional Model(s): SM-F700F/DS, SCV47

Serial Number: 4725J

Antenna Configurations: Internal Antenna **DUT Type:** Portable Handset

#### **Power Reduction for WIFI**

This device uses an independent fixed level power reduction mechanism for all WIFI operations during voice or VoIP held to ear scenarios. Reduced powers were used to evaluate for low-power exemption in Section 9.II for WIFI. Detailed descriptions of the power reduction mechanism are included in the operational description.

#### II. LTE Band Selection

This device supports the following pairs of LTE bands with similar frequencies: LTE B12 & B17, B2 & B25, B4 & B66, and B5 & B26. These pairs of LTE bands have the same target powers and share the same transmission paths. Since the supported frequency spans for the smaller LTE bands are completely covered by the larger LTE bands, only the larger LTE bands (LTE B12, B25, B66, and B26) were evaluated for hearing-aid compliance.

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#### Table 2-1 SM-F700F & SM-F700F/DS HAC Air Interfaces

CIVITYOUT & CIVITYOUT / DO TING / III III.CITAGES							
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service		
	850						
GSM	1900	VO	Yes	Yes: WIFI or BT	CMRS Voice		
	GPRS/EDGE	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo		
	850						
UMTS	1700	VD	No <sup>1</sup>	Yes: WIFI or BT	CMRS Voice		
UIVITS	1900						
	HSPA	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo		
	700 (B12)						
	700 (B17)						
	780 (B13)						
LTE (FDD)	850 (B5)		No <sup>1</sup>	No <sup>1</sup> Yes: WIFI or BT	VoLTE, Google Duo		
	850 (B26)	VD					
LIE (FDD)	1700 (B4)	VD					
	1700 (B66)						
	1900 (B2)						
	1900 (B25)						
	2300 (B30)						
LTE (TDD)	2600 (B41)	VD	Yes	Yes: WIFI or BT	VoLTE, Google Duo		
	2450						
	5200 (U-NII 1)						
WIFI	5300 (U-NII 2A)	VD	No <sup>1</sup>	Yes: GSM, UMTS, or LTE	VoWIFI, Google Duo		
	5500 (U-NII 2C)						
	5800 (U-NII 3)						
BT	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A		
Type Transport			Notes:				
	VO = Voice Only DT = Digital Data - Not intended for Voice Services			or MIF and low-power exemption.			
DI – DIBITAI DA	ta - NOT IIITEIIGEG IOI	voice services					

VD = CMRS and/or IP Voice over Data Transport

#### Table 2-2 SCV47 HAC Air Interfaces

			HAC Tested	Simultaneous But Not Tested	Name of Voice Service	
	850	VO	Yes	Yes: WIFI or BT	CMRS Voice	
GSM	1900	VO	res	res: WIFI OF BT	CIVIRS VOICE	
	GPRS/EDGE	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo	
LINATE	850	VD	No <sup>1</sup>	Yes: WIFI or BT	CMRS Voice	
UMTS	HSPA	VD	No <sup>1</sup>	Yes: WIFI or BT	Google Duo	
	700 (B12)					
LTE (FDD) 780 (B13) 850 (B5)	780 (B13)	VD	No <sup>1</sup>	Yes: WIFI or BT	VoLTE, Google Duo	
	850 (B5)					
LTE (TDD)	2600 (B41)	VD	Yes	Yes: WIFI or BT	VoLTE, Google Duo	
	2450					
	5200 (U-NII 1)					
WIFI	5300 (U-NII 2A)	VD	No <sup>1</sup>	Yes: GSM, UMTS, or LTE	VoWIFI, Google Duo	
	5500 (U-NII 2C)		1			
	5800 (U-NII 3)					
ВТ	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A	

Type Transport VO = Voice Only

Notes:

1. Evaluated for MIF and low-power exemption.

DT = Digital Data - Not intended for Voice Services VD = CMRS and/or IP Voice over Data Transport

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## 3. ANSI/IEEE C63.19 PERFORMANCE CATEGORIES

### I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters		
Near field Category	E-field emissions CW dB(V/m)		
	f < 960 MHz		
M1	50 to 55		
M2	45 to 50		
M3	40 to 45		
M4	< 40		
	f > 960 MHz		
M1	40 to 45		
M2	35 to 40		
M3	30 to 35		
M4	< 30		
Table 3-1 WD near-field categories as defined in ANSI C63.19-2011			

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### 4. SYSTEM SPECIFICATIONS

### **EF3DV3 E-Field Probe Description**

Construction: One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

Calibration: In air from 30 MHz to 6.0 GHz

(absolute accuracy ±5.1%, k=2)

Frequency: 30 MHz to > 6 GHz;

Linearity: ± 0.2 dB (30 MHz to 6 GHz)

Directivity  $\pm 0.2 \text{ dB}$  in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range 2 V/m to > 1000 V/m

(M3 or better device readings fall well below diode

compression point)

Linearity: ± 0.2 dB

Dimensions Overall length: 337 mm (Tip: 20 mm)

Tip diameter: 4.0 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 1.5 mm



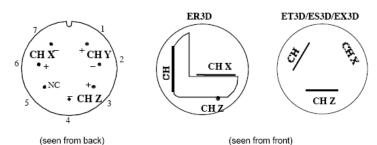
Figure 4-1 E-field Free-space Probe

#### **Probe Tip Description**

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

The electric field probes have an irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement").

#### Connector Plan



The antistatic shielding inside the probe is connected to the probe connector case.

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#### **Instrumentation Chain**

#### **Equation 1**

### Conversion of Connector Voltage u, to E-Field E,

$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

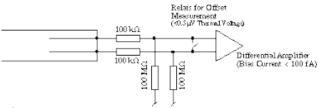
whereby

Eı: electric field in V/m

voltage of channel i at the connector in µV Uí. sensitivity of channel i in µV/(V/m)2 Norm: ConvF: enhancement factor in liquid (ConvF=1 for Air) DCP: diode compression point in µV

CF. signal crest factor (peak power/average power)

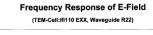
#### Conditions of Calibration



- a lower input impedance of the amplifier will result in different sensitivity factors Norm; and DCP
- larger bias currents will cause higher offset

#### **Probe Response to Frequency**

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).



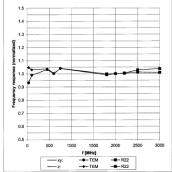


Figure 4-2 E-Field Probe Frequency Response

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#### **SPEAG Robotic System**

E-field measurements are performed using the DASY5 automated dosimetric assessment system. The DASY5 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of high precision robotics system (Staubli), robot controller, Intel CORE i7 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



**Figure 4-3** SPEAG Robotic System

#### **System Hardware**

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the computer with operating system and RF Measurement Software DASY5 v52.8 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

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#### **System Electronics**

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.

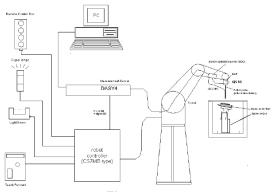


Figure 4-4 SPEAG Robotic System Diagram

#### **DASY5 Instrumentation Chain**

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

$$\begin{aligned} V_i &= U_i + U_i^2 \cdot \frac{cf}{dcp_i} \\ \text{with} \quad V_i &= \text{compensated signal of channel i} & (i = x, y, z) \\ U_i &= \text{input signal of channel i} & (i = x, y, z) \\ cf &= \text{crest factor of exciting field} & (\text{DASY parameter}) \\ dcp_i &= \text{diode compression point} & (\text{DASY parameter}) \end{aligned}$$

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From the compensated input signals the primary field data for each channel can be evaluated:

$$\mathbf{E} - \text{fieldprobes}: \qquad E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

with  $V_i$  = compensated signal of channel i  $Norm_i$  = sensor sensitivity of channel i (i = x, y, z)(i = x, v, z)

 $\mu V/(V/m)^2$  for E-field Probes

= sensitivity enhancement in solution

= electric field strength of channel i in V/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500ms.

The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500ms and a probe response time of <5 ms. In the current implementation, DASY5 waits longer than 100ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

#### **Environmental Conditions**

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

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## 5. TEST PROCEDURE

#### I. RF EMISSIONS

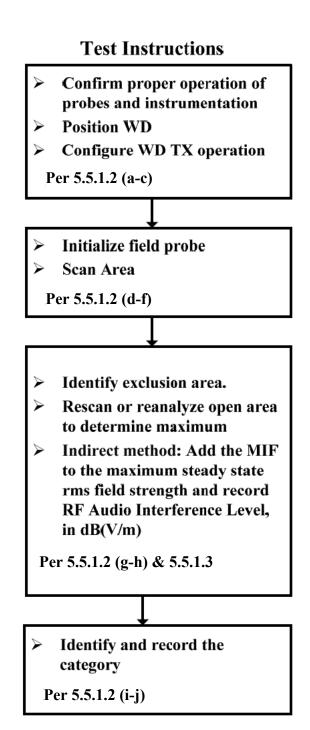


Figure 5-1 RF Emissions Flow Chart

	_			
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### **Test Setup**

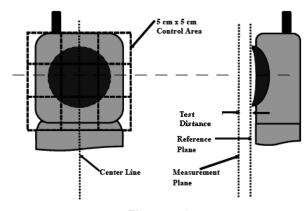


Figure 5-2 E-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)

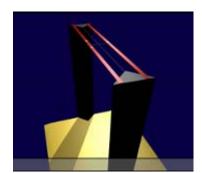


Figure 5-3 **HAC** Phantom

#### **RF Emissions Test Procedure:**

The following illustrate a typical RF emissions test scan over a wireless communications device:

- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- 3. The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm or 5mm increments in the 5 x 5 cm region were performed at a distance 15 mm from the center point of the probe measurement element to the WD. Of the 9 subgrids (see Figure 5-2), 3 contiguous subgrids may be excluded from the measurement in order to account for localized areas of higher field intensities. The center subgrid containing the acoustic output or audio band magnetic output may not excluded. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location. If the power drift deviated by more than 5%, the HAC test and drift measurements were repeated.

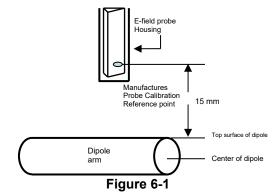
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#### 6. SYSTEM CHECK

### **System Check Parameters**

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 15 mm probe to dipole separation, which is measured from top surface of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device [e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (20dBm) RMS] after adjustment for any mismatch.

### Validation Procedure

A dipole antenna meeting the requirements given in C63.19 was placed in the position normally occupied by the WD.

The length of the dipole was scanned, and the average peak value was recorded.

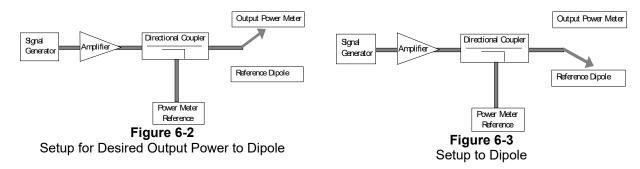
#### Measurement of CW

Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (see manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

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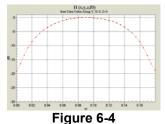
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RF power was recorded using both an average and a peak power reading meter.



Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 6-3.

The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



2-D Raw Data from scan along dipole axis

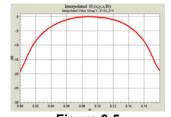
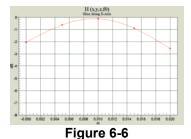


Figure 6-5
2-D Interpolated points from scan along dipole axis



2-D Raw Data from scan along transverse axis



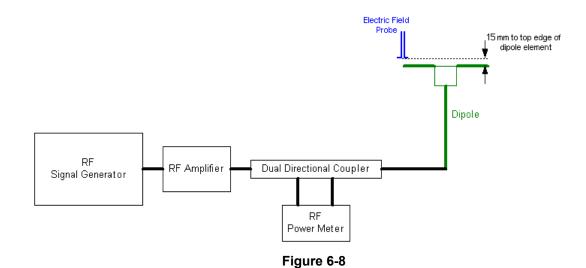
2-D Interpolated points from scan along transverse axis

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## III. System Check Results

### **Validation Results**

Date	Frequency (MHz)	Probe S/N	DAE S/N	Dipole S/N	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation	
12/23/2019	835			1003	20.0	105.6	105.2	0.4%	
12/23/2019	1880	4035	1415	1415	1137	20.0	90.0	87.8	2.5%
12/30/2019	2600			1012	20.0	87.2	85.2	2.3%	



System Check Setup

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#### **MODULATION INTERFERENCE FACTOR** 7.

#### I. **Measuring Modulation Interference Factors**

For any specific fixed and repeatable modulated signal, a modulation interference factor (MIF, expressed in dB) may be determined that relates its interference potential to its steady-state RMS signal level or average power level. This factor is a function only of the audio-frequency amplitude modulation characteristics of the signal and is the same for field-strength and conducted power measurements. The MIF is valid only for a specific repeatable audio-frequency amplitude modulation characteristic; any change in modulation characteristic requires determination and application of a new MIF.

The MIF may be determined using a radiated RF field or a conducted RF signal:

- a. Using RF illumination or conducted coupling, apply the specific modulated signal in question to the measurement system at a level within its confirmed operating dynamic range.
- b. Measure the steady-state RMS level at the output of the fast probe or sensor.
- Measure the steady-state average level at the weighting output.
- d. Without changing the square-law detector or weighting system, and using RF illumination or conducted coupling, substitute for the specific modulated signal a 1 kHz, 80% amplitude modulated carrier at the same frequency and adjust its strength until the level at the weighting output equals the step c) measurement.
- e. Without changing the carrier level from step d), remove the 1 kHz modulation and again measure the steady-state RMS level indicated at the output of the fast probe or sensor.
- The MIF for the specific modulation characteristic is provided by the ratio of the step e) measurement to the step b) measurement, expressed in dB (20 × log[(step e)/(step b)]).

The following procedure was used to measure the MIF using the SPEAG Audio Interference Analyzer (AIA), Type No: SE UMS 170 CB, Serial No.: 1010:

- 1. The device was placed into a simulated call using a base station simulator or set to transmit using test software for a given mode.
- 2. The device was then set to continuously transmit at maximum power.
- 3. Using a coupler if needed, the device output signal was connected to the RF In port of the AIA, which was connected to a desktop computer. Alternatively, a radiated RF signal may be used with the AIA's built-in antenna.
- 4. The MIF measurement procedure in the DASY software was run, and the resulting MIF value was recorded.
- Steps 1-4 were repeated for all CMRS air interfaces, frequency bands, and modulations.

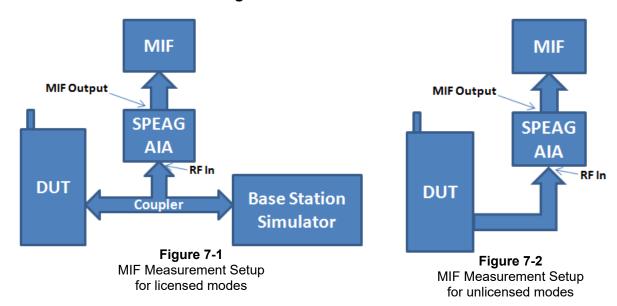
The modulation interference factors obtained were applied to readings taken of the actual wireless device in order to obtain an accurate audio interference level reading using the formula:

#### Audio Interference Level [dB(V/m)] = 20 \* log[Raw Field Value (V/m)] + MIF (dB)

Because the MIF value is output power independent, MIF values for a given mode should be constant across all devices; however, per C63.19-2011 §D.7, MIF values should be measured for each device being evaluated. The voice modes for this device have been investigated in this section of the report.

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## II. MIF Measurement Block Diagrams



### **III. Measured Modulation Interference Factors:**

**Table 7-1**GSM Modulation Interference Factors<sup>1</sup>

Mode		GSM850			GSM1900		
IVIC	ue	128	190	251	512	661	810
GSM	Voice	3.52	3.53	3.52	3.51	3.52	3.52
GSIVI	EDGE	3.73	3.72	3.74	3.66	3.68	3.66

**Table 7-2**UMTS Modulation Interference Factors<sup>1</sup>

OWITO Modulation interference ractors												
Mo	Mode 4132		UMTS V		UMTS IV			UMTS II				
IVIC			4183	4233	1312	1412	1513	9262	9400	9538		
	12.2 kbps RMC	-23.08	-23.62	-23.11	-23.37	-23.84	-22.78	-23.01	-23.91	-23.19		
UMTS	12.2 kbps AMR	-23.94	-24.11	-24.43	-24.11	-24.23	-24.10	-24.28	-24.53	-23.73		
	HSUPA Subtest1	-22.71	-22.69	-22.75	-22.27	-22.38	-22.67	-22.74	-23.27	-22.91		

<sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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Table 7-3 LTE FDD Modulation Interference Factors<sup>1,2</sup>

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
66	1745.0	132322	20	16QAM	1	0	-9.61
25	1882.5	26365	20	16QAM	1	0	-10.28
26	831.5	26865	15	16QAM	1	0	-9.86
12	707.5	23095	10	16QAM	1	0	-9.92
13	782.0	23230	10	16QAM	1	0	-10.84
30	2310.0	27710	10	16QAM	1	0	-10.48
66	1745.0	132322	20	QPSK	1	0	-14.32
66	1745.0	132322	20	64QAM	1	0	-9.91
66	1745.0	132322	20	16QAM	1	50	-10.29
66	1745.0	132322	20	16QAM	1	99	-9.99
66	1745.0	132322	20	16QAM	50	0	-16.42
66	1745.0	132322	20	16QAM	100	0	-16.60
66	1745.0	132322	15	16QAM	1	0	-9.97
66	1745.0	132322	10	16QAM	1	0	-9.92
66	1745.0	132322	5	16QAM	1	0	-10.35
66	1745.0	132322	3	16QAM	1	0	-10.04
66	1745.0	132322	1.4	16QAM	1	0	-9.79
66	1720.0	132072	20	16QAM	1	0	-9.51
66	1770.0	132572	20	16QAM	1	0	-9.69

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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<sup>&</sup>lt;sup>2</sup> Note: All FDD LTE bands were found to have substantially similar MIF values given similar RB, BW, and modulation configurations.

Table 7-4 LTE TDD B41 Power Class 3 Modulation Interference Factors<sup>1,2</sup>

LTE Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	MIF [dB]
41	2593.0	40620	20	16QAM	1	0	3.58
41	2593.0	40620	20	QPSK	1	0	3.56
41	2593.0	40620	20	64QAM	1	0	3.60
41	2593.0	40620	20	64QAM	1	50	3.61
41	2593.0	40620	20	64QAM	1	99	3.60
41	2593.0	40620	20	64QAM	50	0	3.51
41	2593.0	40620	20	64QAM	100	0	3.53
41	2593.0	40620	15	64QAM	1	36	3.59
41	2593.0	40620	10	64QAM	1	25	3.60
41	2593.0	40620	5	64QAM	1	12	3.59
41	2506.0	39750	20	64QAM	1	50	3.62
41	2549.5	40185	20	64QAM	1	50	3.60
41	2636.5	41055	20	64QAM	1	50	3.60
41	2680.0	41490	20	64QAM	1	50	3.59

Table 7-5 LTE TDD Uplink Carrier Aggregation Modulation Interference Factor<sup>1,3</sup>

					PCC				SCC							
c	ombination	PCC Band	PCC Bandwidth [MHz]	PCC (UL/DL)	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	I SCC (UII /DI)	SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	MIF (dB)
С	A_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	3.62

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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<sup>&</sup>lt;sup>2</sup> Note: LTE TDD MIFs were taken using UL-DL Configuration 5. More information about the chosen UL-DL Configuration can be found in Section 10.

 $<sup>^3</sup>$  Note: LTE TDD ULCA was evaluated to ensure LTE TDD standalone was the worst-case scenario. The configuration in Table 7-5 was determined from Table 7-4 and satisfies the configuration requirements as defined in 3GPP 36.101. These MIFs were evaluated with UL-DL Configuration 5 for Power Class 3 LTE TDD.

Table 7-6 802.11b (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

	802.11b MIF Measurements [dB]								
Mode	Data Rate [Mbps]								
	1	2	5.5	11					
802.11b	<b>-</b> 9.39	-11.16	<b>-</b> 9.33	-9.30					

Table 7-7

802.11a (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

		<b>.</b> .	802.1	1g MIF Me	asurement	s [dB]		
Mode	Mode Data Rate [Mbps]							
	6	9	12	18	24	36	48	54
802.11g	-10.22	-9.86	-9.60	<b>-</b> 9.10	-8.82	-9.36	-9.45	-9.63

Table 7-8

802.11g (2.4GHz, MIMO) Modulation Interference Factors<sup>1,2</sup>

			802.1	1g MIF Mea	asurement	s [dB]		
Mode	Data Rate [Mbps]							
	12	18	24	36	48	72	92	108
802.11g	-10.16	-9.81	-9.44	-8.94	-8.70	-8.83	-9.29	-9.40

Table 7-9

802.11n (2.4GHz, SISO) Modulation Interference Factors<sup>1,2</sup>

			802.11n (2	.4GHz) MIF	Measurer	nents [dB]		
Mode	MCS Index							
	0	1	2	3	4	5	6	7
802.11n	-10.52	-9.79	-9.18	-9.01	-9.16	-9.44	-9.49	-9.87

**Table 7-10** 

802.11n (2.4GHz, MIMO) Modulation Interference Factors<sup>1,2</sup>

COL. THE (2. TOTAL, WHITE) Weddiddon Interference Tuestore										
			802.11n (2	.4GHz) MIF	Measure	ments [dB]				
Mode	MCS Index									
	0	1	2	3	4	5	6	7		
802.11n	-11.37	-9.68	-9.13	-9.29	-9.22	-9.11	-9.71	-9.50		

**Table 7-11** 

802.11a (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

	002.114	(00:12, 20		<u> </u>	alation into	110101100 1 0	401010	
			802.1	1a MIF Mea	asurement	s [dB]		
Mode	Data Rate [Mbps]							
	6	9	12	18	24	36	48	54
802.11a	-11.67	-10.94	-10.48	-9.85	-9.41	-9.69	-10.15	-10.39

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>&</sup>lt;sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

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**Table 7-12**802.11a (5GHz. 20MHz BW. MIMO) Modulation Interference Factors<sup>1,2</sup>

		•	802.1	1a MIF Mea	asurement	s [dB]		
Mode	Data Rate [Mbps]							
	12	18	24	36	48	72	92	108
802.11a	-11.67	-10.97	-9.42	-9.66	-9.40	-9.66	-10.12	-10.35

#### **Table 7-13**

802.11n (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		20MHz BW 802.11n (5GHz) MIF Measurements [dB]										
Mode	MCS Index 0 1 2 3 4 5 6 7											
802.11n	-11.95	-10.81	-9.94	<b>-</b> 9.70	-9.84	-10.25	-10.45	-10.75				

**Table 7-14** 

802.11n (5GHz, 20MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		20MI	Hz BW 802	.11n (5GHz	) MIF Mea	surements	[dB]				
Mode		MCS Index									
	0	1	2	3	4	5	6	7			
802.11n	-11.95	-10.94	-10.00	-9.49	-9.86	-10.28	-10.47	-10.77			

#### **Table 7-15**

802.11ac (5GHz, 20MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

	002.	. 1 lac (3Gl	IZ, ZUIVII IZ	DVV, 3130	) Modulatio		FILE FACIO	15					
		20MHz BW 802.11ac (5GHz) MIF Measurements [dB]											
Mode	de MCS Index												
	0	1	2	3	4	5	6	7	8				
802.11ac	-10.91	-9.88	-9.68	-10.05	-10.82	-11.53	-11.79	-12.05	-12.21				

### **Table 7-16**

802.11ac (5GHz, 20MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

802.11ac (5GHz, 20MHz BW, MIMO) Modulation Interference Factors -													
		20MHz BW 802.11ac (5GHz) MIF Measurements [dB]											
Mode MCS Index													
	0 1 2 3 4 5 6 7 8												
802.11ac	-11.90	-10.78	-9.97	-9.72	-9.71	-10.20	-10.33	-10.64	-11.04				

### **Table 7-17**

802.11n (5GHz, 40MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		40MI	Hz BW 802	.11n (5GHz	) MIF Mea	surements	[dB]			
Mode	MCS Index									
	0	1	2	3	4	5	6	7		

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

<sup>&</sup>lt;sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

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#### **Table 7-18** 802.11n (5GHz, 40MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		40MI	lz BW 802	.11n (5GHz	) MIF Mea	surements	[dB]			
Mode	MCS Index									
	0	1	2	3	4	5	6	7		
802.11n	-9.63	-8.90	-9.14	-9.60	-10.62	-11.71	-11.92	-12.13		

#### **Table 7-19**

802.11ac (5GHz, 40MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

		,	40MH	Iz BW 802.	11ac (5GH	z) MIF Mea	surement	s [dB]		
Mode	MCS Index									
	0	1	2	3	4	5	6	7	8	9
802.11ac	-9.64	-8.79	-9.13	-9.56	-10.60	-11.65	-11.87	-12.08	N/A	-12.96

#### **Table 7-20**

802 11ac (5GHz 40MHz BW MIMO) Modulation Interference Factors<sup>1,2</sup>

		2.1140 (0				z) MIF Mea				
Mode	Mode MCS Index									
	0	1	2	3	4	5	6	7	8	9
802.11ac	-8.84	-9.46	-10.47	-11.41	-12.20	-13.18	-13.48	-13.75	N/A	-14.34

#### **Table 7-21**

802.11ac (5GHz, 80MHz BW, SISO) Modulation Interference Factors<sup>1,2</sup>

			80MH	z BW 802.	11ac (5GH	z) MIF Mea	surement	s [dB]		
Mode	MCS Index 0 1 2 3 4 5 6 7 8 9									
802.11ac	-9.22	-9.94	-10.93	-11.87	-12.70	-13.45	-13.71	-13.90	-14.32	-14.59

#### **Table 7-22**

802.11ac (5GHz, 80MHz BW, MIMO) Modulation Interference Factors<sup>1,2</sup>

		,	80MH	Iz BW 802.	11ac (5GH	z) MIF Mea	surement	s [dB]		
Mode	MCS Index									
	0	1	2	3	4	5	6	7	8	9
802.11ac	<b>-</b> 9.89	-11.56	-12.31	-13.00	-13.83	-14.48	-14.46	-14.56	-14.48	-14.54

<sup>&</sup>lt;sup>1</sup> Note: Measured MIF values may be lower than sample MIF values provided in ANSI C63.19-2011 Annex D.7 Table D.5 due to manufacturing variations for each device, however per Annex D.7, the sample MIF values of Table D.5 are not intended to substitute for measurements of actual devices under test and their respective operating modes.

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<sup>&</sup>lt;sup>2</sup> Note: WIFI MIF values were found to be independent of the transmit channel.

#### 8. RF CONDUCTED POWER MEASUREMENTS

### **Procedures Used to Establish RF Signal for HAC Testing**

The handset was configured to transmit the required air interface in a shielded chamber. Measurements were taken with a fully charged battery.

#### II. **HAC Measurement Conditions**

#### **Output Power Verification**

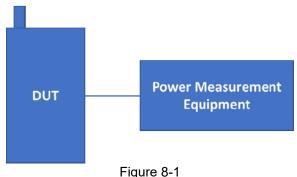
Maximum output power is verified on the High, Middle and Low channels for all applicable air interfaces for which full testing scans are required. Modes which are exempted from full testing according to Section 9 of this report have only their conducted power targets listed below, not measured values. See Table 8-1 for air interface specific settings of transmit power parameters. See Table 9-1 for more information regarding which modes required full testing and had conducted power measurements taken.

> Table 8-1 Power Control Parameters and Settings by Air Interface

	iiti oi i ai aiiiotoi o aiia o	stange by tan interrace		
Air Interface:	Parameter Name:	Parameter Set To:		
GSM	PCL	GSM850: "5"; GSM1900: "0"		
UMTS	TPC	"All 1's"		
LTE	TPC	"Max Power"		
WIFI	Mfr Configured	Mfr Specified		

### III. Setup Used to Measure RF Conducted Powers

The general setup for conducted power is shown in Figure 8-1 below. The power measurement equipment could be a base station simulator, signal analyzer, or power meter depending on the applicable air interface.



Power Measurement Setup

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### **IV. GSM Conducted Powers**

Band	Channel	GSM [dBm] CS (1 Slot)	EDGE [dBm] 1 Tx Slot
	128	32.98	27.36
GSM 850	190	33.03	27.56
	251	32.98	27.60
	512	29.00	25.20
GSM 1900	661	29.72	25.54
	810	29.42	25.51

## V. UMTS Target Powers

Table 8-2 UMTS Conducted Power Targets

		M	odulated A	verage (dB	m)
Mode / Band		3GPP	3GPP	3GPP	3GPP
		WCDMA	HSDPA	HSUPA	DC-HSDPA
UMTS Band 5 (850 MHz)	Maximum	25.0	23.0	23.0	23.0
OIVITS Ballu 5 (850 IVIH2)	Nominal	24.0	22.0	22.0	22.0
UMTS Band 4 (1750 MHz)	Maximum	24.0	22.5	22.5	22.5
UIVITS BAITU 4 (1750 IVITZ)	Nominal	23.0	21.5	21.5	21.5
UMTS Band 2 (1900 MHz)	Maximum	25.0	23.0	23.0	23.0
OIVITS DATIU 2 (1900 IVITI2)	Nominal	24.0	22.0	22.0	22.0

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## **VI. LTE FDD Target Powers**

Table 8-3 LTE FDD Conducted Power Targets

Mode / Band	 	Modulated Average (dBm)
177.0	Maximum	25.7
LTE Band 12	Nominal	24.7
LTC Donal 17	Maximum	24.7
LTE Band 17	Nominal	23.7
LTE Band 13	Maximum	25.7
LIE Dallu 15	Nominal	24.7
LTE Band 26 (Cell)	Maximum	25.7
LTE Ballu 20 (Cell)	Nominal	24.7
LTE Band 5 (Cell)	Maximum	25.7
LTL Balla 3 (Cell)	Nominal	24.7
LTE Band 66 (AWS)	Maximum	25.2
LTE Barid 00 (AW3)	Nominal	24.2
LTE Band 4 (AWS)	Maximum	25.0
LTL ballu 4 (AVV3)	Nominal	24.0
LTE Band 25 (PCS)	Maximum	25.1
LTL Datid 25 (1 C5)	Nominal	24.1
LTE Band 2 (PCS)	Maximum	25.1
LTL Dana 2 (T C3)	Nominal	24.1
LTE Band 30	Maximum	25.7
LIL Dalla 30	Nominal	24.7

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### **VII. LTE TDD Conducted Powers**

### a. LTE Band 41 Power Class 3

Table 8-4 LTE Band 41 (2593 0MHz) Conducted Powers - 20MHz Bandwidth

				20	LTE Band 41 0 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [de	Bm]			
	1	0	23.82	24.00	24.27	24.45	24.02		0
	1	50	23.83	24.04	24.30	24.41	24.18	0	0
	1	99	23.86	24.05	24.32	24.28	24.25		0
QPSK	50	0	22.91	23.19	23.55	23.49	23.30	0-1	1
	50	25	22.99	23.19	23.54	23.51	23.42		1
	50	50	22.92	23.12	23.52	23.40	23.41		1
	100	0	22.92	23.11	23.51	23.46	23.35		1
	1	0	22.87	23.13	23.53	23.62	23.33		1
	1	50	22.70	23.10	23.56	23.44	23.29	0-1	1
	1	99	22.80	23.13	23.42	23.12	23.40		1
16QAM	50	0	21.97	22.34	22.76	22.67	22.49		2
	50	25	21.98	22.32	22.73	22.56	22.52	0-2	2
	50	50	21.95	22.22	22.58	22.42	22.51	0-2	2
	100	0	21.96	22.29	22.74	22.57	22.52		2
	1	0	21.86	21.93	22.27	22.35	22.04		2
	1	50	21.78	21.82	22.19	22.17	21.95	0-2	2
	1	99	21.82	21.83	22.13	22.07	21.87		2
64QAM	50	0	20.99	21.39	21.64	21.54	21.31		3
	50	25	20.98	21.36	21.61	21.58	0-3	0-3	3
	50	50	20.99	21.27	21.48	21.48	21.04	_	3
	100	0	20.95	21.27	21.52	21.51	21.15		3

Table 8-5 LTE Band 41 (2593.0MHz) Conducted Powers - 15MHz Bandwidth

			,	0.0111112) 00	LTE Band 41		mile Balla		
				1	MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [di	ßm]			
	1	0	24.21	24.42	24.77	24.63	24.41		0
	1	36	24.19	24.54	24.88	24.58	24.51	0	0
	1	74	24.26	24.48	24.79	24.42	24.53		0
QPSK	36	0	23.29	23.62	23.93	23.72	23.57		1
	36	18	23.34	23.66	23.97	23.69	23.65	0-1	1
	36	37	23.30	23.57	23.92	23.62	23.65	0-1	1
	75	0	23.24	23.58	23.90	23.64	23.59		1
	1	0	23.12	23.64	23.62	23.87	23.32		1
	1	36	23.11	23.70	23.77	23.82	23.41	0-1	1
	1	74	23.14	23.62	23.65	23.61	23.43		1
16QAM	36	0	22.32	22.64	22.97	22.66	22.66		2
	36	18	22.39	22.67	23.06	22.64	22.72	0-2	2
	36	37	22.40	22.61	22.96	22.53	22.68	0-2	2
	75	0	22.31	22.56	22.92	22.60	22.64		2
	1	0	22.04	22.32	22.50	22.73	22.25		2
	1	36	21.98	22.43	22.50	22.66	22.20	0-2	2
	1	74	22.06	22.33	22.33	22.46	21.91		2
64QAM	36	0	21.32	21.63	21.87	21.64	21.64		3
	36	18	21.38	21.66	21.91	21.58	21.60	0.2	3
	36	37	21.40	21.60	21.80	21.49	21.48	0-3	3
	75	0	21.32	21.57	21.80	21.70	21.55	Ī	3

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Table 8-6 LTE Band 41 (2593.0MHz) Conducted Powers - 10MHz Bandwidth

			,	10	LTE Band 41 MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Cor	nducted Power [dE	Bm]			
	1	0	24.03	24.62	24.78	24.42	24.28		0
	1	25	24.13	24.40	24.45	24.56	24.17	0	0
	1	49	23.94	24.52	24.69	24.51	24.24		0
QPSK	25	0	23.19	23.54	23.82	23.62	23.46	0-1	1
	25	12	23.20	23.56	23.84	23.61	23.44		1
	25	25	23.16	23.51	23.75	23.57	23.39	0-1	1
	50	0	23.19	23.51	23.83	23.57	23.47		1
	1	0	23.35	23.38	24.02	23.70	23.46		1
	1	25	23.04	23.23	24.02	23.54	23.58	0-1	1
	1	49	23.33	23.25	23.95	23.57	23.41		1
16QAM	25	0	22.13	22.58	22.78	22.62	22.40		2
	25	12	22.16	22.57	22.76	22.58	22.45	0-2	2
	25	25	22.05	22.57	22.70	22.52	22.39		2
	50	0	22.15	22.58	22.81	22.59	22.42		2
	1	0	22.27	22.59	22.77	22.38	22.28		2
	1	25	21.84	22.42	22.77	21.89	22.45	0-2	2
	1	49	22.18	22.50	22.66	22.26	22.22	Ţ	2
64QAM	25	0	21.09	21.58	21.75	21.63	21.41		3
	25	12	21.13	21.61	21.78	21.62	21.41	0-3	3
	25	25	21.06	21.55	21.70	21.65	21.35		3
	50	0	21.24	21.57	21.78	21.64	21.47	Ī	3

Table 8-7 LTE Band 41 (2593 0MHz) Conducted Powers - 5MHz Bandwidth

		LILD	and 41 (23	3.01VII 12) C	LTE Band 41	owers – 5	MI IZ Dalluv	viatii	
					MHz Bandwidth				
			Low Channel	Low-Mid Channel	Mid Channel	Mid-High Channel	High Channel		
Modulation	RB Size	RB Offset	39750 (2506.0 MHz)	40185 (2549.5 MHz)	40620 (2593.0 MHz)	41055 (2636.5 MHz)	41490 (2680.0 MHz)	MPR Allowed per 3GPP [dB]	MPR [dB]
				Co	nducted Power [de	Bm]			
	1	0	24.06	24.56	24.65	24.49	24.29		0
	1	12	24.06	24.54	24.65	24.52	24.29	0	0
	1	24	24.17	24.58	24.67	24.53	24.28		0
QPSK	12	0	23.21	23.48	23.73	23.50	23.42		1
	12	6	23.26	23.60	23.77	23.55	23.45	0-1	1
	12	13	23.29	23.56	23.81	23.55	23.48		1
	25	0	23.22	23.57	23.77	23.62	23.40		1
	1	0	22.87	23.57	23.43	23.25	23.11	0-1	1
	1	12	22.84	23.57	23.44	23.23	23.06		1
	1	24	22.96	23.60	23.50	23.25	23.14		1
16QAM	12	0	22.28	22.55	22.83	22.57	22.47		2
	12	6	22.35	22.70	22.91	22.61	22.50	0-2	2
	12	13	22.28	22.66	22.88	22.65	22.54	0-2	2
	25	0	22.30	22.51	22.83	22.58	22.42		2
	1	0	22.18	22.87	22.81	22.49	22.43		2
	1	12	22.14	22.95	22.84	22.52	22.40	0-2	2
	1	24	22.22	22.93	22.77	22.46	22.39	Ī	2
64QAM	12	0	21.24	21.52	21.76	21.63	21.38		3
	12	6	21.22	21.64	21.78	21.61	21.46	0.3	3
	12	13	21.22	21.61	21.85	21.66	21.47	0-3	3
	25	0	21.20	21.46	21.72	21.57	21.42		3

## b. LTE Uplink Carrier Aggregation

Table 8-8 LTE Uplink Two Component Carrier Aggregation Conducted Powers

			Opini	K I WO	Comp	OHEHL	Carrie	י רששי	egani	)II 00I	luucte	u i ow	CIS		
				PCC							scc				Power
Combination	PCC Band	PCC Bandwidth [MHz]	PCC (III /DI)	PCC (UL/DL) Frequency [MHz]	Modulation	PCC UL# RB	PCC UL RB Offset	SCC Band	SCC Bandwidth [MHz]	SCC (III /DI)	SCC (UL/DL) Frequency [MHz]		SCC UL# RB	SCC UL RB Offset	LTE Tx.Power with UL CA Enabled
CA_41C (PC3)	LTE B41	20	40620	2593.0	16QAM	1	0	LTE B41	20	40422	2573.2	16QAM	1	99	23.72

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## VIII. WIFI Target Powers (SISO/MIMO)

Table 8-9
IEEE 802.11a/b/g/n/ac Reduced Average RF Power Targets<sup>1</sup>

			002	ia/k	<i>n</i> griira	CINEU	Reduced Average RF Fower Targets									
Mode	Band			SISO (Ant 1	)			9	SISO (Ant 2	.)			MII	MO		
Wiouc	Dana	а	b	g	n	ac	а	b	g	n	ac	а	g	n	ac	
2.4GHz	2.45GHz		12	12	12			12	12	12			15	15		
	5200MHz	10			10	10	10			10	10	13		13	13	
5GHz (20MHz)	5300MHz	10			10	10	10			10	10	13		13	13	
3GI 12 (20IVII 12)	5500MHz	10			10	10	10			10	10	13		13	13	
	5800MHz	10			10	10	10			10	10	13		13	13	
	5200MHz				10	10				10	10			13	13	
5GHz (40MHz)	5300MHz				10	10				10	10			13	13	
3GHZ (40IVIHZ)	5500MHz				10	10				10	10			13	13	
	5800MHz				10	10				10	10			13	13	
	5200MHz					10					10				13	
5GHz (80MHz)	5300MHz					10					10				13	
SUNZ (80IVIAZ)	5500MHz					10					10				13	
	5800MHz					10					10				13	

(Upper tolerance: target +1.0dB)

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<sup>&</sup>lt;sup>1</sup> Note: This device utilizes independent power reduction mechanisms for the WIFI transmitter in all WIFI modes for held-to-ear scenarios.

### 9. JUSTIFICATION OF HELD TO EAR MODES TESTED

### I. Analysis of RF Air Interface Technologies

An analysis was performed, following the guidance of §4.3 and §4.4 of the ANSI standard, of the RF air interface technologies being evaluated. The factors that will affect the RF interference potential were evaluated, and the worst-case operating modes were identified and used in the evaluation. A WD's interference potential is a function both of the WD's average near-field field strength and of the signal's audio-frequency amplitude modulation characteristics. Per §4.4, RF air interface technologies that have low power have been found to produce sufficiently low RF interference potential, so it is possible to exempt them from the product testing specified in Clause 5 of the ANSI standard. An RF air interface technology of a device is exempt from testing when its average antenna input power plus its MIF is ≤17dBm for all of its operating modes. RF air interface technologies exempted from testing in this manner are automatically assigned an M4 rating to be used in determining the overall rating for the WD.

The worst-case MIF plus the worst-case average antenna input power for all modes are investigated below to determine the testing requirements for this device.

#### II. Individual Mode Evaluations

Table 9-1
Max Power + MIF calculations for Low Power Exemptions

Wax Tower Time Saledian				
Air Interface	Maximum Average Power (dBm)	Worst Case MIF (dB)	Total (Power + MIF, dB)	C63.19 Testing Required
GSM - GSM850	24.00*	3.53	27.53	Yes
GSM - GSM1900	20.69*	3.52	24.21	Yes
GSM - EDGE850	18.57*	3.74	22.31	Yes**
GSM - EDGE1900	16.51*	3.68	20.19	Yes**
UMTS - RMC	25.00	-22.78	2.22	No
UMTS - AMR	25.00	-23.73	1.27	No
UMTS - HSPA	23.00	-22.27	0.73	No
LTE FDD	25.70	-9.51	16.19	No
LTE TDD - Band 41 (PC3)	15.17*	3.62	18.79	Yes
LTE TDD - Uplink Carrier Aggregation	14.01*	3.62	17.63	Yes***
WIFI - 2.4GHz	16.00	-8.70	7.30	No
WIFI - 5GHz	14.00	-8.79	5.21	No

<sup>\*</sup> Note: ANSI C63.19-2011 Sec. 4.4 Footnote 20 indicates the use of a long averaging time for measuring the antenna input power when using this method of exclusion. Therefore, the frame averaged power was calculated for these modes in this investigation.

### III. Low-Power Exemption Conclusions

Per ANSI C63.19-2011, RF Emissions testing for this device is required only for GSM voice modes as well as LTE TDD Power Class 3 data modes. All other air interfaces are exempt.

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<sup>\*\*</sup> Note: EDGE data modes were considered but not tested as GSM voice modes were found to be the worst-case modes for the GSM air interface.

<sup>\*\*\*</sup> Note: LTE TDD ULCA data modes were considered but not tested as LTE TDD non-CA modes were found to be the worst-case modes for the LTE TDD air interface.

#### 10. LTE TDD UPLINK-DOWNLINK CONFIGURATION

### **Uplink-Downlink Configuration Additional Testing**

Additional testing was performed on each supported power class for LTE TDD to determine the worst-case Uplink-Downlink configuration for RFE testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length  $T_f = 307200 \cdot T_s = 10$ ms, where T<sub>s</sub> is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length  $30720 \cdot T_s = 1$  ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192 · Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

> **Table 10-1** Unlink-Downlink Configurations for Type 2 Frame Structures

Uplink-downlink configuration	Downlink-to-Uplink Switch-point periodicity				Calculated Transmission							
configuration	Switch-point periodicity	0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)
0	5 ms	D	S	U	U	U	D	S	U	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	U	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	U	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

### II. Power Class 3 Uplink-Downlink Configuration Additional Testing

LTE TDD was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst-case emission was used for full testing. See Table 10-2 below for results. The configuration determined in the results below was used to measure the MIF values in Table 7-4.

> **Table 10-2** LTE TDD Power Class 3 UL-DL Configuration Results

Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.		RB Size	RB Offset	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissi	ions														
	20	40620	0	16QAM	1	0	Acoustic	8.25	18.33	-3.34	14.99	35.00	-20.01	M4	1,2,3
	20	40620	1	16QAM	1	0	Acoustic	6.68	16.49	-1.51	14.98	35.00	-20.02	M4	1,2,3
	20	40620	2	16QAM	1	0	Acoustic	4.86	13.73	1.42	15.15	35.00	-19.85	M4	1,2,3
LTE TDD / Band 41	20	40620	3	16QAM	1	0	Acoustic	6.29	15.97	-1.42	14.55	35.00	-20.45	M4	1,2,3
	20	40620	4	16QAM	1	0	Acoustic	5.28	14.45	0.75	15.20	35.00	-19.80	M4	1,2,3
	20	40620	5	16QAM	1	0	Acoustic	4.13	12.31	3.58	15.89	35.00	-19.11	M4	1,2,3
	20	40620	6	16QAM	1	0	Acoustic	7.74	17.77	-2.52	15.25	35.00	-19.75	M4	1,2,3

#### III. Conclusion

Per the results above, UL-DL Configuration 5 was used for LTE TDD Power Class 3 testing.

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## 11. OVERALL MEASUREMENT SUMMARY

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### I. E-FIELD EMISSIONS:

Table 11-1
HAC Data Summary for F-field - GSN

	HAC Data Summary for E-field - GSM														
Mode	Channel	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5				
E-Field Emissi	ons														
	128	Acoustic	32.98	31.47	29.96	3.52	33.48	45.00	-11.52	M4	7,8,9				
GSM850	190	Acoustic	33.03	29.20	29.31	3.53	32.84	45.00	-12.16	M4	7,8,9				
GSIVIOSU	251	Acoustic	32.98	31.34	29.92	3.52	33.44	45.00	-11.56	M4	7,8,9				
	128	T-Coil	32.98	30.37	29.65	3.52	33.17	45.00	-11.83	M4	6,8,9				
	512	Acoustic	29.00	9.16	19.24	3.51	22.75	35.00	-12.25	M4	7,8,9				
GSM1900	661	Acoustic	29.72	8.48	18.57	3.52	22.09	35.00	-12.91	M4	7,8,9				
	810	Acoustic	29.42	7.67	17.69	3.52	21.21	35.00	-13.79	M4	7,8,9				

Table 11-2
HAC Data Summary for E-field – LTE TDD Band 41

	TIAO Data Callinary for E field ETE 100 Balla 41															
Mode / Band	Bandwidth (MHz)	Channel	UL-DL Config.		RB Size	RB Offset	Scan Center	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
E-Field Emissi	ions															
	20	39750	5	64QAM	1	50	Acoustic	21.78	3.89	11.80	3.62	15.42	35.00	-19.58	M4	1,2,3
	20	40185	5	64QAM	1	50	Acoustic	21.82	3.86	11.73	3.60	15.33	35.00	-19.67	M4	3,6,9
LTE TDD / Band 41 PC3	20	40620	5	64QAM	1	50	Acoustic	22.19	3.72	11.41	3.61	15.02	35.00	-19.98	M4	1,2,3
	20	41055	5	64QAM	1	50	Acoustic	22.17	3.55	10.99	3.60	14.59	35.00	-20.41	M4	1,2,3
	20	41490	5	64QAM	1	50	Acoustic	21.95	3.73	11.44	3.59	15.03	35.00	-19.97	M4	7,8,9

## II. Worst-case Configuration Evaluation

Table 11-3
Peak Reading 360° Probe Rotation at Azimuth axis

Mode	Channel	Scan Center	Time Avg. Field (V/m)	Time Avg. Field [dB(V/m)]	MIF (dB)	Audio Interference Level [dB(V/m)]	FCC Limit (dBV/m)	FCC Margin (dB)	Result	Excl Blocks per 5.5
Probe Rotatio	Probe Rotation at Worst-Case									
GSM850	128	Acoustic	32.92	30.35	3.52	33.87	45.00	-11.13	M4	7,8,9

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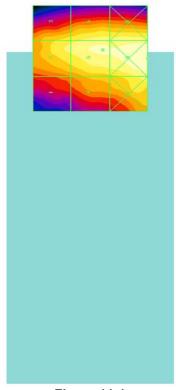
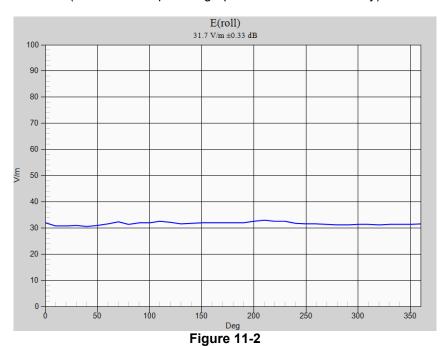


Figure 11-1 Sample E-field Scan Overlay (See Test Setup Photographs for actual WD overlay)



\* Note: Locations of probe rotation (with and without exclusions) are shown in Figure 11-1 denoted by the green square markers.

**Worst-Case Probe Rotation about Azimuth axis** 

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#### **EQUIPMENT LIST** 12.

**Table 12-1 Equipment List** 

Manufacturer Model		Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	E4438C	ESG Vector Signal Generator	5/23/2019	Annual	5/23/2020	MY47270002
Agilent	N5182A	MXG Vector Signal Generator	7/10/2019	Annual	7/10/2020	MY47420800
Amplifier Research	15S1G6	Amplifier	N/A	CBT*	N/A	433978
Anritsu	MT8821C	Radio Communication Analyzer	1/25/2019	Annual	1/25/2020	6261895213
Anritsu	MA24106A	USB Power Sensor	1/31/2019	Annual	1/31/2020	1520503
Anritsu	MA24106A	USB Power Sensor	1/31/2019	Annual	1/31/2020	1520501
Anritsu	MA2411B	Pulse Power Sensor	3/6/2019	Annual	3/6/2020	1339018
Anritsu	MA2411B	Pulse Power Sensor	8/8/2019	Annual	8/8/2020	1339008
Anritsu	ML2496A	Power Meter	11/6/2019	Annual	11/6/2020	1405003
Control Company	4040	Temperature / Humidity Monitor	2/28/2018	Biennial	2/28/2020	150761911
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	N/A	CBT*	N/A	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	N/A	CBT*	N/A	1226
Pasternack	PE2237-20	Bidirectional Coupler	N/A	CBT*	N/A	N/A
Rohde & Schwarz	CMW500	Radio Communication tester	8/14/2019	Annual	8/14/2020	140144
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	1/30/2019	Annual	1/30/2020	162125
Seekonk	NC-100	Torque Wrench (8" lb)	5/23/2018	Biennial	5/23/2020	N/A
SPEAG	AIA	Audio Interference Analzyer	N/A	CBT*	N/A	1010
SPEAG	EF3DV3	Freespace E-field Probe	1/16/2019	Annual	1/16/2020	4035
SPEAG	CD2600V3	Freespace 2600MHz Dipole	2/19/2019	Biennial	2/19/2021	1012
SPEAG	CD835V3	Freespace 835 MHz Dipole	2/19/2019	Biennial	2/19/2021	1003
SPEAG	CD1880V3	Freespace 1880 MHz Dipole	2/19/2019	Biennial	2/19/2021	1137
SPEAG	DAE4	Dasy Data Acquisition Electronics	3/13/2019	Annual	3/13/2020	1415

Calibration traceable to the National Institute of Standards and Technology (NIST).

\*Note: CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, attenuator, coupler or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

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### 13. MEASUREMENT UNCERTAINTY

# Table 13-1 Uncertainty Estimation Table

Uncertainty Estimation Table Wireless Communications Device Near-Field Measurement							
Uncertainty Estimation							
Uncertainty Component	Data (dB)	Data Type	Prob. Dist.	Divisor	Ci (E)	Unc. (dB)	Notes/Comments
Measurement System	=		-			-	-
RF System Reflections	0.50	Tolerance	N	1.00	1	0.50	* Refl. < -20 dB
Field Probe Calibration	0.21	Tolerance	N	1.00	1	0.21	
Field Probe Isotropy	0.01	Tolerance	N	1.00	1	0.01	
Field Probe Frequency Response	0.135	Tolerance	N	1.00	1	0.14	
Field Probe Linearity	0.013	Tolerance	N	1.00	1	0.01	
Modulation Interference Factor	0.20	Tolerance	R	1.73	1	0.12	Applicable for M-rating testing
Boundary Effects	0.105	Accuracy	R	1.73	1	0.06	*
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	1	0.12	*
Probe Positioner	0.050	Accuracy	R	1.73	1	0.03	*
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	1	0.03	*
Resolution to 2mm error	0.21	Tolerance	N	1.00	1	0.21	
System Detection Limit	0.05	Tolerance	R	1.73	1	0.03	*
Readout Electronics	0.015	Tolerance	N	1.00	1	0.02	*
Integration Time	0.11	Tolerance	R	1.73	1	0.06	*
Response Time	0.033	Tolerance	R	1.73	1	0.02	*
Phantom Thickness	0.10	Tolerance	R	1.73	1	0.06	*
System Repeatability (Field x 2=power)	0.17	Tolerance	N	1.00	1	0.17	*
Test Sample Related							
Device Positioning Vertical	0.2	Tolerance	R	1.73	1	0.12	*
Device Positioning Lateral	0.045	Tolerance	R	1.73	1	0.03	*
Device Holder and Phantom	0.1	Tolerance	R	1.73	1	0.06	*
Power Drift	0.21	Tolerance	R	1.73	1	0.12	
Combined Standard Uncertainty (k=1)		0.66	16.3%				
Expanded Uncertainty [95% confidence]						1.31	32.6%
Expanded Uncertainty [95% confidence] on Field						0.66	16.3%

#### Notes:

- Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All
  equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81
  and NIST Tech Note 1297 and UKAS M3003.
- 2. \* Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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#### TEST DATA 14.

See following Attached Pages for Test Data.

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#### DUT: CD835V3 - SN1003

Type: CD835V3 Serial: 1003

#### Communication System: CW; Frequency: 835 MHz;

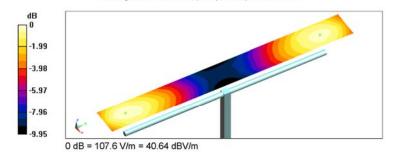
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- · Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
  Measurement SW: DASY52, Version 52.10 (0);

#### 835 MHz / 100mW HAC Dipole Validation at 15mm / Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 126.8 V/m; Power Drift = -0.01 dB Applied MIF = 0.00 dB Average Value of Peak (interpolated) = 105.6 V/m



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### DUT: CD1880V3 - SN1137

Type: CD1880V3 Serial: 1137

#### Communication System: CW; Frequency: 1880 MHz;

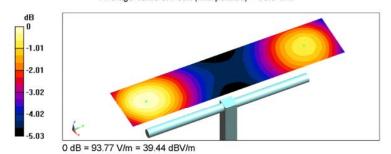
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- · Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### 1880 MHz / 100mW HAC Dipole Validation at 15mm / Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 148.3 V/m; Power Drift = -0.00 dB Applied MIF = 0.00 dB Average Value of Peak (interpolated) = 90.0 V/m



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#### DUT: CD2600V3 - SN1012

Type: CD2600V3 Serial: 1012

#### Communication System: CW; Frequency: 2600 MHz;

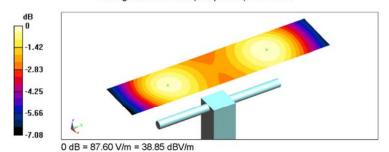
Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### 2600 MHz / 100mW HAC Dipole Validation at 15mm / Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 68.91 V/m; Power Drift = -0.06 dB Applied MIF = 0.00 dB Average Value of Peak (interpolated) = 87.2 V/m



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#### **DUT: A3LSMF700F**

Type: Portable Handset Serial: 4725J Backlight off Duty Cycle: 1:8.3

## Communication System: GSM; Frequency: 824.2 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

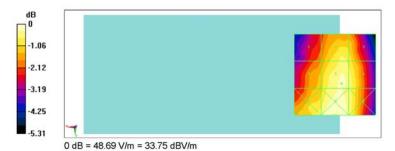
- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### GSM850 Low Channel / Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 42.86 V/m; Power Drift = -0.10 dB Applied MIF = 3.52 dB RF audio interference level = 33.48 dBV/m Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
31.98 dBV/m	33.14 dBV/m	32.93 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
32.57 dBV/m	33.48 dBV/m	33.25 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
33.26 dBV/m	33.75 dBV/m	33.29 dBV/m



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Date: 12/28/2019



#### **DUT: A3LSMF700F**

Type: Portable Handset Serial: 4725J Backlight off Duty Cycle: 1:8.3

#### Communication System: GSM; Frequency: 1850.2 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

#### GSM1900 Low Channel / Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 5.152 V/m; Power Drift = 0.17 dB Applied MIF = 3.51 dB RF audio interference level = 22.75 dBV/m Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
22.75 dBV/m	22.05 dBV/m	20.65 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
18.67 dBV/m	21.06 dBV/m	21.63 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
23.89 dBV/m	24.6 dBV/m	24.05 dBV/m



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#### **DUT: A3LSMF700F**

Type: Portable Handset Serial: 4725J Backlight off Duty Cycle: 1:9.35

#### Communication System: LTE TDD41; Frequency: 2506 MHz;

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY5 Configuration:

- Probe: EF3DV3 SN4035; Calibrated: 1/16/2019;
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn1415; Calibrated: 3/13/2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA;
- Measurement SW: DASY52, Version 52.10 (0);

# Power Class 3 TDD LTE Band 41 Low Channel, UL-DL 5, 20MHz, 64QAM, 1RB, 50RB Offset Hearing Aid Compatibility Test (101x101x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 2.375 V/m; Power Drift = 0.10 dB
Applied MIF = 3.62 dB
RF audio interference level = 15.42 dBV/m
Emission category: M4

#### MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
14.64 dBV/m	15.36 dBV/m	16.66 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
12.1 dBV/m	13.4 dBV/m	12.54 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
12.45 dBV/m	14.51 dBV/m	15.42 dBV/m



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#### CALIBRATION CERTIFICATES 15.

The following pages include the probe calibration used to evaluate HAC for the DUT.

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#### Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Certificate No: EF3-4035 Jan19/2

Multilateral Agreement for the recognition of calibration certifi

Client PC Test

			f No: EF3-4035_Jan	

Object

EF3DV3- SN:4035

Calibration procedure(s)

QA CAL-02.v9, QA CAL-25.v7

Calibration procedure for E-field probes optimized for close near field

evaluations in air

Calibration date:

January 16, 2019

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673)	Apr-19
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19
Power sensor NRP-Z91	SN: 103245	04-Apr-18 (No. 217-02673)	Apr-19
Reference 20 dB Attenuator	SN: S5277 (20x)	04-Apr-18 (No. 217-02682)	Apr-19
DAE4	SN: 789	14-Jan-19 (No. DAE4-789_Jan19)	Jan-20
Reference Probe ER3DV6	SN: 2328	09-Oct-18 (No. ER3-2328_Oct18)	Oct-19
Secondary Standards	ID	Check Date (in house)	Scheduled Check
Power meter E4419B	SN: GB41293874	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: MY41498087	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
Power sensor E4412A	SN: 000110210	06-Apr-16 (in house check Jun-18)	In house check: Jun-20
RF generator HP 8648C	SN: US3642U01700	04-Aug-99 (in house check Jun-18)	In house check: Jun-20
Network Analyzer E8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19

	Name	Function	Signature	
Calibrated by:	Manu Seitz	Laboratory Technician		•
			and the second	
Approved by:	Katja Pokovic	Technical Manager	600	
			15-1-15-	

Issued: February 11, 2019

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: EF3-4035\_Jan19/2

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#### Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étatonnage C Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z sensitivity in free space DCP diode compression point

CF crest factor (1/duty\_cycle) of the RF signal A, B, C, D modulation dependent linearization parameters En incident E-field orientation normal to probe axis incident E-field orientation parallel to probe axis Ep

Polarization φ φ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., 9 = 0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system

#### Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
b) CTIA Test Plan for Hearing Aid Compatibility, Rev 3.1.1, May 2017

#### Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization  $\vartheta=0$  for XY sensors and  $\vartheta=90$  for Z sensor (f  $\leq 900$  MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z \* frequency\_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

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# DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

#### **Basic Calibration Parameters**

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm $(\mu V/(V/m)^2)$	0.90	0.74	1.20	± 10.1 %
DCP (mV) <sup>B</sup>	96.8	98.5	95.3	

Calibration results for Frequency Response (30 MHz - 6 GHz)

Frequency MHz	Target E-Field V/m	Measured E-field (En) V/m	Deviation E-normal in %	Measured E-field (Ep) V/m	Deviation E-normal in %	Unc (k=2) %
30	77.3	76.8	-0.6%	77.3	0.1%	± 5.1 %
100	77.3	78.2	1.2%	77.8	0.7%	± 5.1 %
450	77.1	78.2	1.5%	77.8	0.9%	± 5.1 %
600	77.1	77.8	0.9%	77.5	0.5%	± 5.1 %
750	77.3	77.7	0.5%	77.2	-0.1%	± 5.1 %
1800	140.3	136.9	-2.4%	137.2	-2.2%	± 5.1 %
2000	133.0	129.4	-2.8%	129.4	-2.7%	± 5.1 %
2200	124.8	121.5	-2.7%	122.7	-1.7%	± 5.1 %
2500	123.7	120.7	-2.4%	121.9	-1.5%	± 5.1 %
3000	78.8	74.8	-5.0%	76.1	-3.5%	± 5.1 %
3500	256.3	248.1	-3.2%	246.0	-4.0%	± 5.1 %
3700	249.7	239.2	-4.2%	239.0	-4.3%	± 5.1 %
5200	50.7	50.7	-0.1%	51.2	0.9%	± 5.1 %
5500	49.6	48.9	-1.5%	48.7	-1.9%	± 5.1 %
5800	48.9	49.1	0.4%	49.3	0.8%	± 5.1 %

**Calibration Results for Modulation Response** 

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Max dev.	Unc <sup>□</sup> (k=2)
0	CW	Х	0.0	0.0	1.0	0.00	141.5	+ 3.3 %	± 4.7 %
		Υ	0.0	0.0	1.0		125.6		
		Υ	0.0	0.0	1.0		125.1		

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: EF3-4035\_Jan19/2

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B Numerical linearization parameter: uncertainty not required.
E Uncertainty is determined using the max, deviation from linear response applying rectangular distribution and is expressed for the square of the

# DASY/EASY - Parameters of Probe: EF3DV3 - SN:4035

## **Sensor Frequency Model Parameters**

	Sensor X	Sensor Y	Sensor Z
Frequency Corr. (LF)	0.28	0.21	5.68
Frequency Corr. (HF)	2.82	2.82	2.82

#### **Other Probe Parameters**

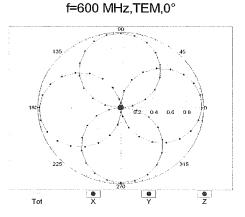
Rectangular
57.9
enabled
disabled
337 mm
12 mm
25 mm
4 mm
1.5 mm
1.5 mm
1.5 mm

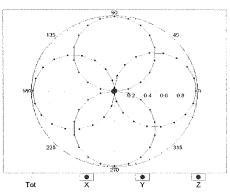
Certificate No: EF3-4035\_Jan19/2

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# Receiving Pattern ( $\phi$ ), $\vartheta = 0^{\circ}$

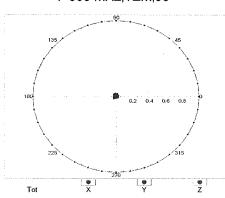




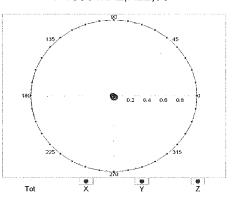
f=1800 MHz,R22,0°

# Receiving Pattern ( $\phi$ ), $9 = 90^{\circ}$

f=600 MHz,TEM,90°



## f=1800 MHz,R22,90°

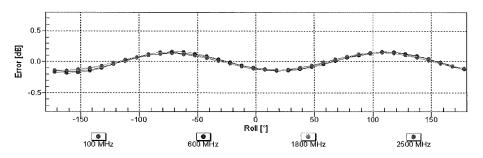


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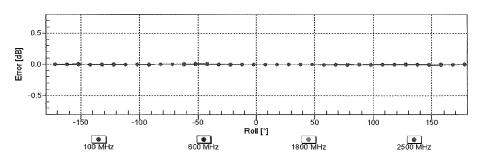
FCC ID: A3LSMF700F	HAC (RF EMISSIONS) TEST REPORT		SAMSUNG	Approved by: Quality Manager
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# Receiving Pattern ( $\phi$ ), $\vartheta = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

# Receiving Pattern ( $\phi$ ), $\vartheta = 90^{\circ}$

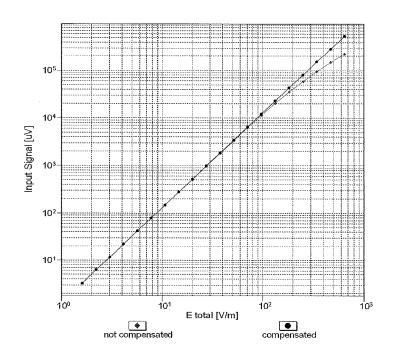


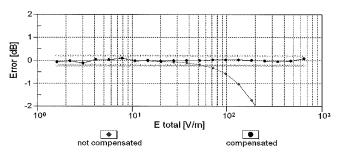
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

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FCC ID: A3LSMF700F	CONTEST:	AC (RF EMISSIONS) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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# Dynamic Range f(E-field) (TEM cell, f = 900 MHz)





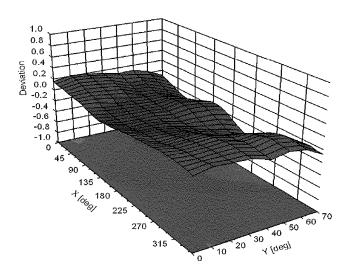
Uncertainty of Linearity Assessment: ± 0.6% (k=2)

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# **Deviation from Isotropy in Air**

Error (φ, θ), f = 900 MHz





Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

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# Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

PC Test

Accreditation No.: SCS 0108

Certificate No: CD835V3-1003\_Feb19

Object	CD835V3 - SN:	1003	
Calibration procedure(s)	QA CAL-20.v7 Calibration Proc	edure for Validation Sources in ai	ir Va4 3/19/201
Calibration date:	February 19, 20	19	
This calibration certificate docum	nents the traceability to nat	ional standards, which realize the physical un	its of measurements (SI).
		probability are given on the following pages an	
All calibrations have been condu	cted in the closed laborato	ry facility: environment temperature (22 $\pm$ 3)°(	C and humidity < 70%.
Calibration Equipment used (M&	TE critical for calibration)		
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter NRP	SN: 104778	04-Apr-18 (No. 217-02672/02673)	Apr-19
Power sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672)	Apr-19
	SN: 103245	04-Apr-18 (No. 217-02673)	·
	SN: 103245 SN: 5058 (20k)	04-Apr-18 (No. 217-02673) 04-Apr-18 (No. 217-02682)	Apr-19
Reference 20 dB Attenuator		04-Apr-18 (No. 217-02682)	Apr-19 Apr-19
Power sensor NRP-Z91 Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3	SN: 5058 (20k)	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683)	Apr-19 Apr-19 Apr-19
Reference 20 dB Attenuator Type-N mismatch combination	SN: 5058 (20k) SN: 5047.2 / 06327	04-Apr-18 (No. 217-02682)	Apr-19 Apr-19
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4 Secondary Standards	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19) Check Date (in house)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781  ID # SN: GB42420191 SN: US38485102	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17) 05-Jan-10 (in house check Oct-17)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check In house check: Oct-20 In house check: Oct-20
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781  ID # SN: GB42420191	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17) 05-Jan-10 (in house check Oct-17) 09-Oct-09 (in house check Oct-17)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check In house check: Oct-20 In house check: Oct-20 In house check: Oct-20
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A RF generator R&S SMT-06	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781  ID # SN: GB42420191 SN: US38485102 SN: US37295597	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17) 05-Jan-10 (in house check Oct-17)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check In house check: Oct-20 In house check: Oct-20
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A RF generator R&S SMT-06 Network Analyzer HP 8358A	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781  ID # SN: GB42420191 SN: US38485102 SN: US37295597 SN: 832283/011	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17) 05-Jan-10 (in house check Oct-17) 09-Oct-09 (in house check Oct-17) 27-Aug-12 (in house check Oct-17)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20 Scheduled Check In house check: Oct-20 In house check: Oct-19
Reference 20 dB Attenuator Type-N mismatch combination Probe EF3DV3 DAE4  Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP 8482A RF generator R&S SMT-06	SN: 5058 (20k) SN: 5047.2 / 06327 SN: 4013 SN: 781  ID # SN: GB42420191 SN: US38485102 SN: US37295597 SN: 832283/011 SN: US41080477	04-Apr-18 (No. 217-02682) 04-Apr-18 (No. 217-02683) 03-Jan-19 (No. EF3-4013_Jan19) 09-Jan-19 (No. DAE4-781_Jan19)  Check Date (in house) 09-Oct-09 (in house check Oct-17) 05-Jan-10 (in house check Oct-17) 09-Oct-09 (in house check Oct-17) 27-Aug-12 (in house check Oct-17) 31-Mar-14 (in house check Oct-18)	Apr-19 Apr-19 Apr-19 Jan-20 Jan-20  Scheduled Check In house check: Oct-20

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# Calibration Laboratory of Schmid & Partner

Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

#### References

 ANSI-C63.19-2011
 American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids,

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
  (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
  In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
  distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network
  Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was
  eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
  obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by th	ie
coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%	6.

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## **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

#### Maximum Field values at 835 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	105.2 V/m = 40.44 dBV/m
Maximum measured above low end	100 mW input power	105.1 V/m = 40.43 dBV/m
Averaged maximum above arm	100 mW input power	105.2 V/m ± 12.8 % (k=2)

# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

Frequency	Return Loss	Impedance	
800 MHz	17.6 dB	40.4 Ω - 7.2 jΩ	
835 MHz	25.8 dB	52.2 Ω + 4.7 jΩ	
880 MHz	16.9 dB	62.1 Ω - 10.5 jΩ	
900 MHz	16.9 dB	52.2 Ω - 14.6 jΩ	
945 MHz	21.6 dB	$51.8 \Omega + 8.3 j\Omega$	

### 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

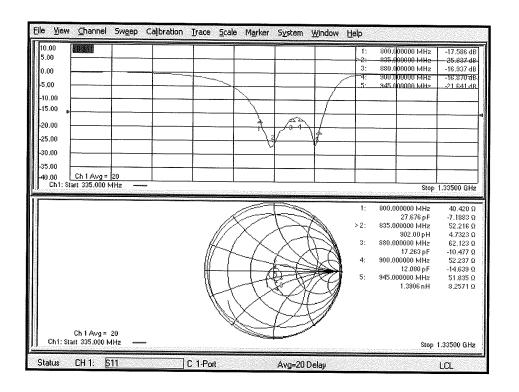
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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## **Impedance Measurement Plot**



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#### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

#### DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1003

Communication System: UID 0 - CW; Frequency: 835 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\epsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

#### DASY52 Configuration:

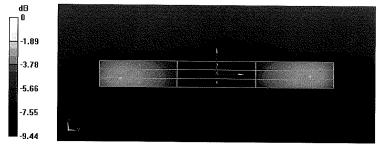
- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 835 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

## Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 127.3 V/m; Power Drift = 0.04 dB Applied MIF = 0.00 dBRF audio interference level = 40.44 dBV/m Emission category: M3

MIF scaled E-field

Grid 1 M4	Grid 2 <b>M3</b>	Grid 3 <b>M3</b>
39.75 dBV/m	40.43 dBV/m	40.43 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
35.35 dBV/m	35.75 dBV/m	35.73 dBV/m
Grid 7 <b>M3</b>	Grid 8 <b>M3</b>	Grid 9 <b>M3</b>
40.15 dBV/m	40.44 dBV/m	40.36 dBV/m



0 dB = 105.2 V/m = 40.44 dBV/m

Certificate No: CD835V3-1003\_Feb19

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# Calibration Laboratory of

**PC Test** 

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

Certificate No: CD1880V3-1137 Feb19

#### **CALIBRATION CERTIFICATE** Object CD1880V3 - SN: 1137 Calibration procedure(s) QA CAL-20.v7 Calibration Procedure for Validation Sources in air Calibration date: February 19, 2019 This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate. All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^{\circ}$ C and humidity < 70%. Calibration Equipment used (M&TE critical for calibration) Primary Standards Cal Date (Certificate No.) Scheduled Calibration Power meter NRP SN: 104778 04-Apr-18 (No. 217-02672/02673) Apr-19 Power sensor NRP-Z91 SN: 103244 04-Apr-18 (No. 217-02672) Apr-19 Power sensor NRP-Z91 SN: 103245 04-Apr-18 (No. 217-02673) Apr-19 Reference 20 dB Attenuator SN: 5058 (20k) 04-Apr-18 (No. 217-02682) Apr-19 Type-N mismatch combination SN: 5047.2 / 06327 04-Apr-18 (No. 217-02683) Apr-19 Probe EF3DV3 SN: 4013 03-Jan-19 (No. EF3-4013\_Jan19) Jan-20 DAE4 SN: 781 09-Jan-19 (No. DAE4-781\_Jan19) Jan-20 Secondary Standards ID# Check Date (in house) Scheduled Check Power meter Agilent 4419B SN: GB42420191 09-Oct-09 (in house check Oct-17) In house check: Oct-20 Power sensor HP E4412A SN: US38485102 05-Jan-10 (in house check Oct-17) In house check: Oct-20 Power sensor HP 8482A SN: US37295597 09-Oct-09 (in house check Oct-17) In house check: Oct-20 RF generator R&S SMT-06 SN: 832283/011 27-Aug-12 (in house check Oct-17) In house check: Oct-20 Network Analyzer HP 8358A SN: US41080477 31-Mar-14 (in house check Oct-18) In house check: Oct-19 Name Function Calibrated by: Claudio Leubler Laboratory Technician Approved by: Katia Pokovic Technical Manager Issued: February 20, 2019 This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: CD1880V3-1137\_Feb19

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## Calibration Laboratory of Schmid & Partner

**Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst S Service suisse d'étalonnage Servizio svizzero di taratura **Swiss Calibration Service** 

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

#### References

ANSI-C63.19-2011 [1] American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

	on is stated as the standard uncertainty of measurement multiplied by the distribution corresponds to a coverage probability of approximately 95%.
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## **Measurement Conditions**

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	1730 MHz ± 1 MHz 1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

## Maximum Field values at 1730 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	95.0 V/m = 39.55 dBV/m	
Maximum measured above low end	100 mW input power	94.9 V/m = 39.55 dBV/m	
Averaged maximum above arm	100 mW input power	95.0 V/m ± 12.8 % (k=2)	

### Maximum Field values at 1880 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum	
Maximum measured above high end	100 mW input power	88.9 V/m = 38.98 dBV/m	
Maximum measured above low end	100 mW input power	86.6 V/m = 38.75 dBV/m	
Averaged maximum above arm	100 mW input power	87.8 V/m ± 12.8 % (k=2)	

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# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

#### **Nominal Frequencies**

Frequency	Return Loss	Impedance 54.4 Ω + 6.5 jΩ	
1730 MHz	22.5 dB		
1880 MHz	21.1 dB	55.9 Ω + 7.2 jΩ	
1900 MHz	21.0 dB	59.0 Ω + 3.6 jΩ	
1950 MHz	27.3 dB	53.0 Ω - 3.3 jΩ	
2000 MHz	20.3 dB	$42.4 \Omega + 4.8 j\Omega$	

## 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

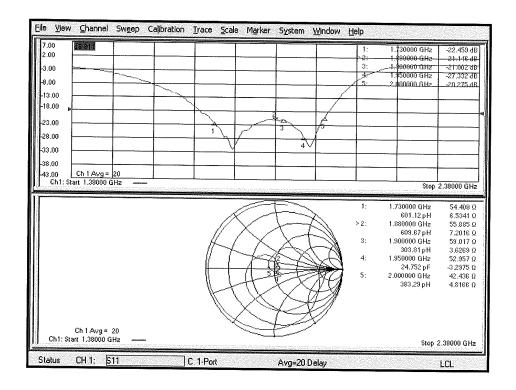
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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## **Impedance Measurement Plot**



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#### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1137

Communication System: UID 0 - CW ; Frequency: 1880 MHz, Frequency: 1730 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\varepsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>2</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 1880 MHz, ConvF(1, 1, 1) @ 1730 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

# Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 151.5 V/m; Power Drift = 0.02 dB Applied MIF = 0.00 dBRF audio interference level = 38.98 dBV/m Emission category: M2

### MIF scaled E-field

Grid 1 <b>M2</b>	Grid 2 <b>M2</b>	Grid 3 <b>M2</b>
38.55 dBV/m	38.98 dBV/m	38.93 dBV/m
Grid 4 <b>M2</b>	Grid 5 M2	Grid 6 <b>M2</b>
35.71 dBV/m	35.97 dBV/m	35.96 dBV/m
Grid 7 <b>M2</b>	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
38.31 dBV/m	38.75 dBV/m	38.73 dBV/m

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# Dipole E-Field measurement @ 1880MHz /E-Scan - 1730MHz d=15mm/Hearing Aid Compatibility Test (41x181x1);

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 165.0 V/m; Power Drift = 0.03 dB

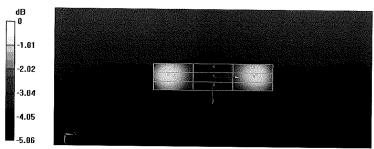
Applied MIF = 0.00 dB

RF audio interference level = 39.55 dBV/m

Emission category: M2

#### MIF scaled E-field

Grid 1 <b>M2</b>	Grid 2 <b>M2</b>	Grid 3 M2
39.09 dBV/m	39.55 dBV/m	39.51 dBV/m
	Grid 5 <b>M2</b>	
36.57 dBV/m	36.95 dBV/m	36.95 dBV/m
Grid 7 M2	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
39.05 dBV/m	39.55 dBV/m	39.53 dBV/m



0 dB = 88.87 V/m = 38.98 dBV/m

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# **Calibration Laboratory of**

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
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Swiss Calibration Service

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The Swiss Accreditation Service is one of the signatories to the EA
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Accreditation No.: SCS 0108

Client

PC Test

Certificate No: CD2600V3-1012 Feb19

CALIBRATION (	CERTIFICAT	<u>E</u>	
Object	CD2600V3 - SN	: 1012	
Calibration procedure(s)	QA CAL-20.v7 Calibration Proc	edure for Validation Sources in a	ir 10A 3/19/2
Calibration date:	February 19, 20	19	
The measurements and the unce	ortainties with confidence p	ional standards, which realize the physical un probability are given on the following pages ar any facility: environment temperature $(22\pm3)^{\circ}$ 0	nd are part of the certificate.
Primary Standards	ID#	Cal Data (Cartificate No.)	0.1.4.1.5.11.11
Power meter NRP	SN: 104778	Cal Date (Certificate No.)	Scheduled Calibration
ower sensor NRP-Z91	SN: 103244	04-Apr-18 (No. 217-02672/02673) 04-Apr-18 (No. 217-02672)	Apr-19
ower sensor NRP-Z91	SN: 103245		Apr-19
eference 20 dB Attenuator	SN: 5058 (20k)	04-Apr-18 (No. 217-02673)	Apr-19
ype-N mismatch combination	SN: 5047.2 / 06327	04-Apr-18 (No. 217-02682)	Apr-19
robe EF3DV3		04-Apr-18 (No. 217-02683)	Apr-19
AE4	SN: 4013	03-Jan-19 (No. EF3-4013_Jan19)	Jan-20
AC4	SN: 781	09-Jan-19 (No. DAE4-781_Jan19)	Jan-20
econdary Standards	ID#	Check Date (in house)	Scheduled Check
ower meter Agilent 4419B	SN: GB42420191	09-Oct-09 (in house check Oct-17)	In house check: Oct-20
ower sensor HP E4412A	SN: US38485102	05-Jan-10 (in house check Oct-17)	In house check; Oct-20
ower sensor HP 8482A	SN: US37295597	09-Oct-09 (in house check Oct-17)	In house check: Oct-20
F generator R&S SMT-06	SN: 832283/011	27-Aug-12 (in house check Oct-17)	In house check: Oct-20
etwork Analyzer HP 8358A	SN: US41080477	31-Mar-14 (in house check Oct-18)	In house check: Oct-19
officers of the co	Name	Function	Signature
alibrated by:	Claudio Leubler	Laboratory Technician	VXI
	Katja Poković	Technical Manager	
pproved by:			/ 6/0/

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# Calibration Laboratory of Schmid & Partner

Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

#### References

 ANSI-C63.19-2011
 American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

#### Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
  (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
   In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
  distance of 15 mm above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
  figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
  is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
  directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network
  Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was
  eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
  obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 15 mm (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by th
coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%

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#### **Measurement Conditions**

DASY system configuration, as far as not given on page 1

DASY Version	DASY5	V52.10.2
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	15 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	2600 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

## Maximum Field values at 2600 MHz

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	85.6 V/m = 38.65 dBV/m
Maximum measured above low end	100 mW input power	84.7 V/m = 38.56 dBV/m
Averaged maximum above arm	100 mW input power	85.2 V/m ± 12.8 % (k=2)

# Appendix (Additional assessments outside the scope of SCS 0108)

#### **Antenna Parameters**

Frequency	Return Loss	Impedance
2450 MHz	20.5 dB	42.7 Ω - 4.8 jΩ
2550 MHz	32.1 dB	48.9 Ω + 2.2 jΩ
2600 MHz	39.6 dB	50.3 Ω + 1.0 jΩ
2650 MHz	30.4 dB	53.0 Ω + 0.9 jΩ
2750 MHz	20.9 dB	48.9 Ω - 8.9  Ω

## 3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

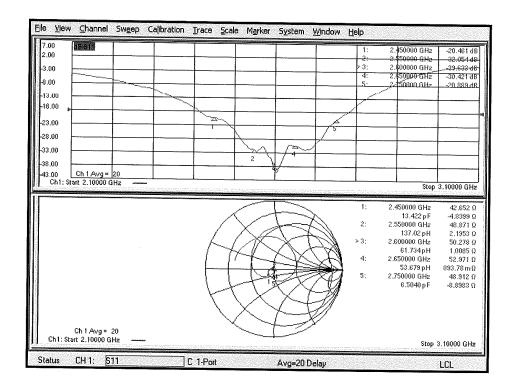
After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

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## **Impedance Measurement Plot**



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#### **DASY5 E-field Result**

Date: 19.02.2019

Test Laboratory: SPEAG Lab2

# DUT: HAC Dipole 2600 MHz; Type: CD2600V3; Serial: CD2600V3 - SN: 1012

Communication System: UID 0 - CW; Frequency: 2600 MHz Medium parameters used:  $\sigma = 0$  S/m,  $\epsilon_r = 1$ ;  $\rho = 0$  kg/m<sup>3</sup> Phantom section: RF Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

## DASY52 Configuration:

- Probe: EF3DV3 SN4013; ConvF(1, 1, 1) @ 2600 MHz; Calibrated: 03.01.2019
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 09.01.2019
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.10.2(1495); SEMCAD X 14.6.12(7450)

# Dipole E-Field measurement @ 2600MHz - with/E-Scan - 2600MHz d=15mm/Hearing Aid Compatibility Test (41x181x1):

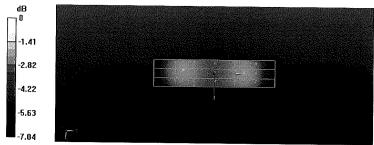
Interpolated grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm Reference Value = 62.82 V/m; Power Drift = -0.01 dB Applied MIF = 0.00 dB

RF audio interference level = 38.65 dBV/m

Emission category: M2

#### MIF scaled E-field

Grid 1 <b>M2</b>	Grid 2 <b>M2</b>	Grid 3 <b>M2</b>
38.09 dBV/m	38.56 dBV/m	38.54 dBV/m
Grid 4 M2	Grid 5 <b>M2</b>	Grid 6 <b>M2</b>
37.82 dBV/m	38.06 dBV/m	38.02 dBV/m
Grid 7 M2	Grid 8 <b>M2</b>	Grid 9 <b>M2</b>
38.36 dBV/m	38.65 dBV/m	38.56 dBV/m



0 dB = 85.60 V/m = 38.65 dBV/m

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#### CONCLUSION 16.

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

Please note that the M-rating for this equipment only represents the field interference possible against a hypothetical and typical hearing aid. The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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